

## Supporting information

### Crystallization of amorphous anodized TiO<sub>2</sub> nanotube arrays

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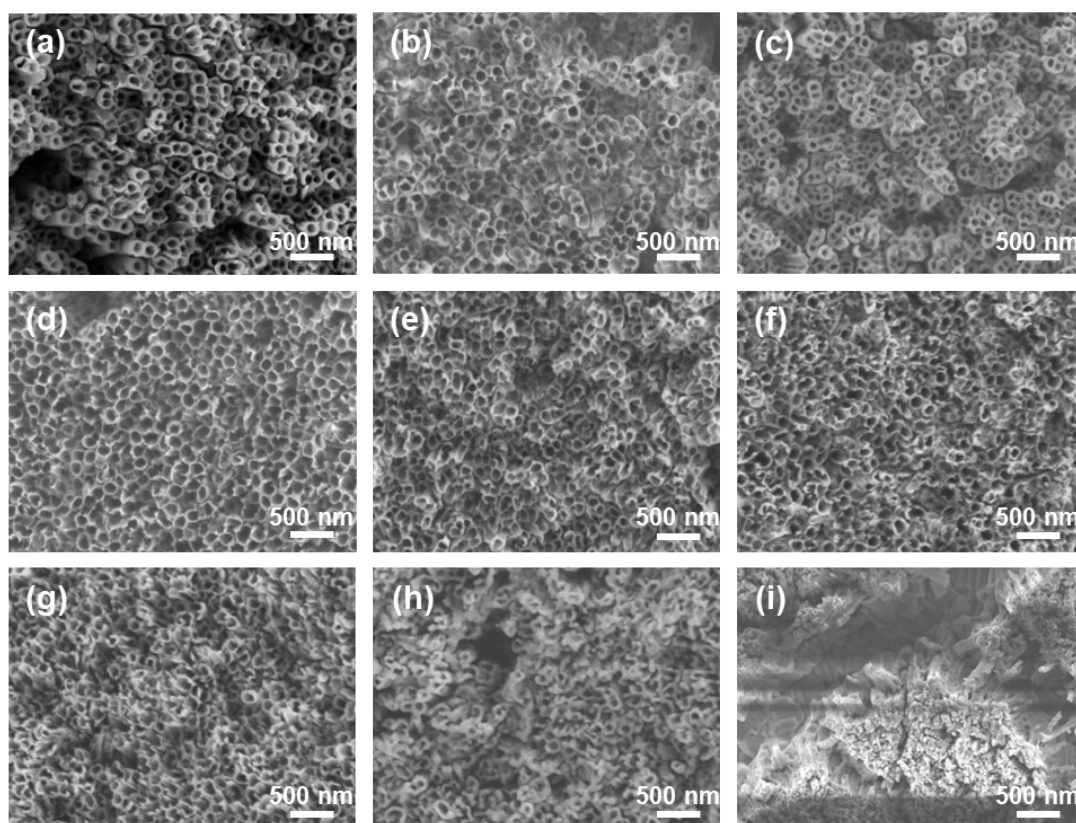


Fig. S1 SEM images of TNTAs grown for 5 h and annealed at different temperatures:  
(a) 100 °C, (b) 200 °C, (c) 300 °C, (d) 400 °C, (e) 500 °C, (f) 600 °C, (g) 700 °C, (h)  
800 °C, (i) 900 °C

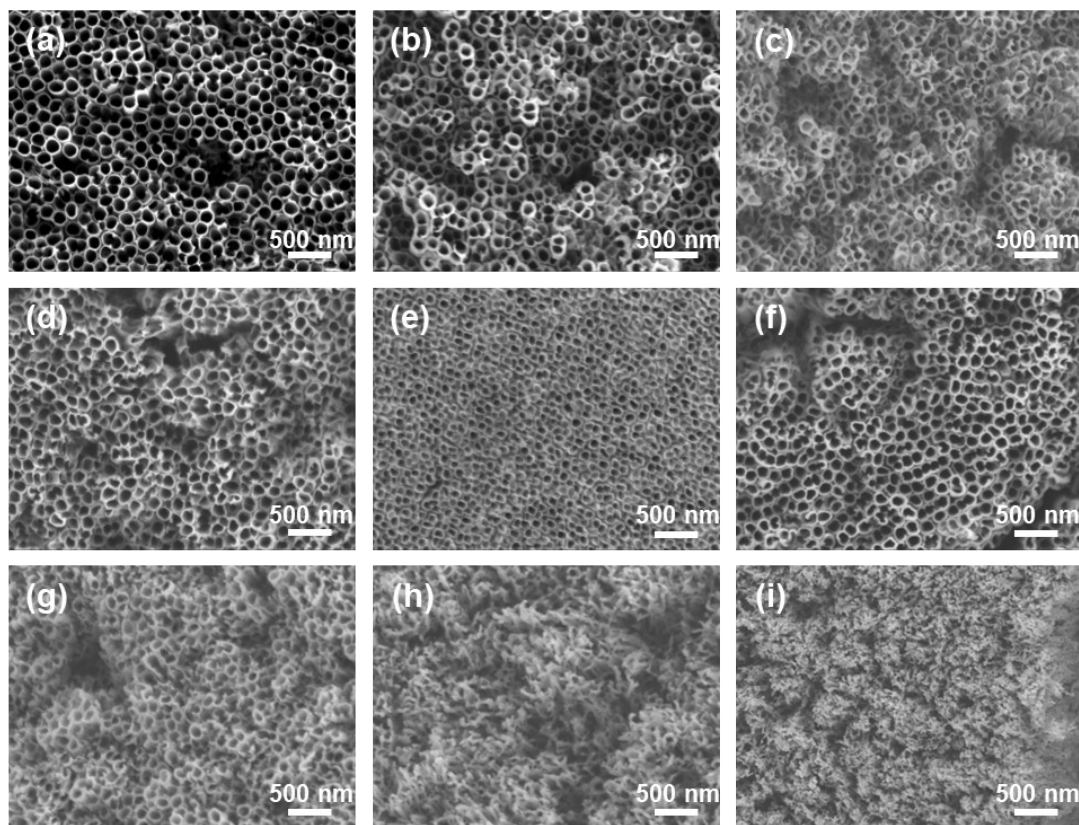


Fig. S2 SEM images of TNTAs grown for 10 h and annealed at different temperatures:  
(a) 100 °C, (b) 200 °C, (c) 300 °C, (d) 400 °C, (e) 500 °C, (f) 600 °C, (g) 700 °C, (h)  
800 °C, (i) 900 °C

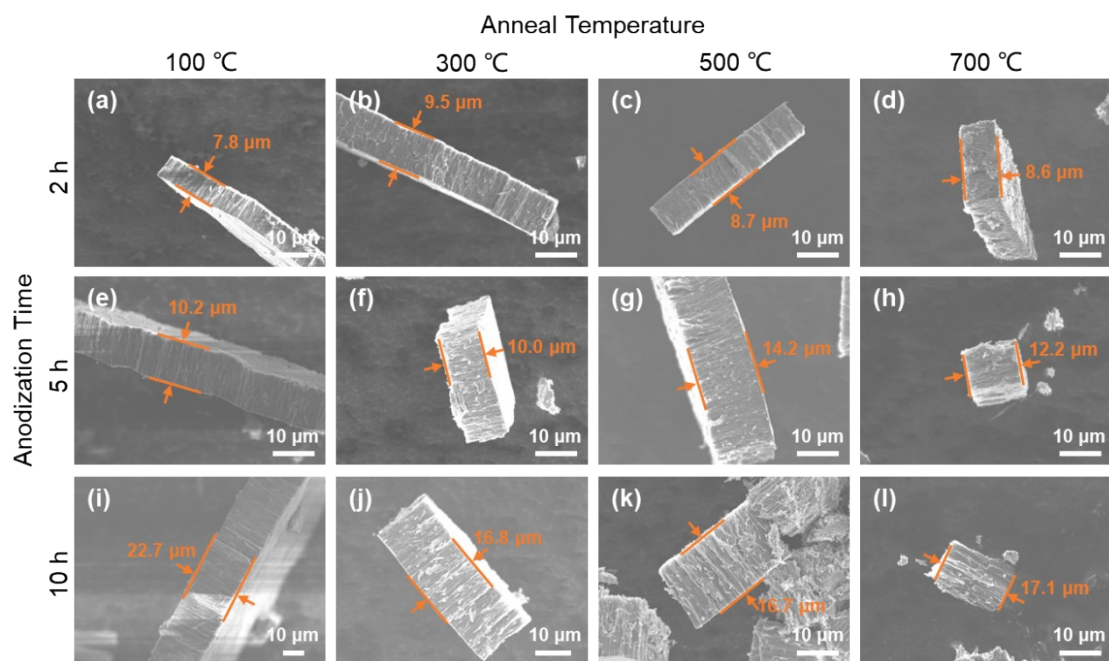


Fig. S3 SEM images of nanotubes with varying anodization times and annealing temperatures

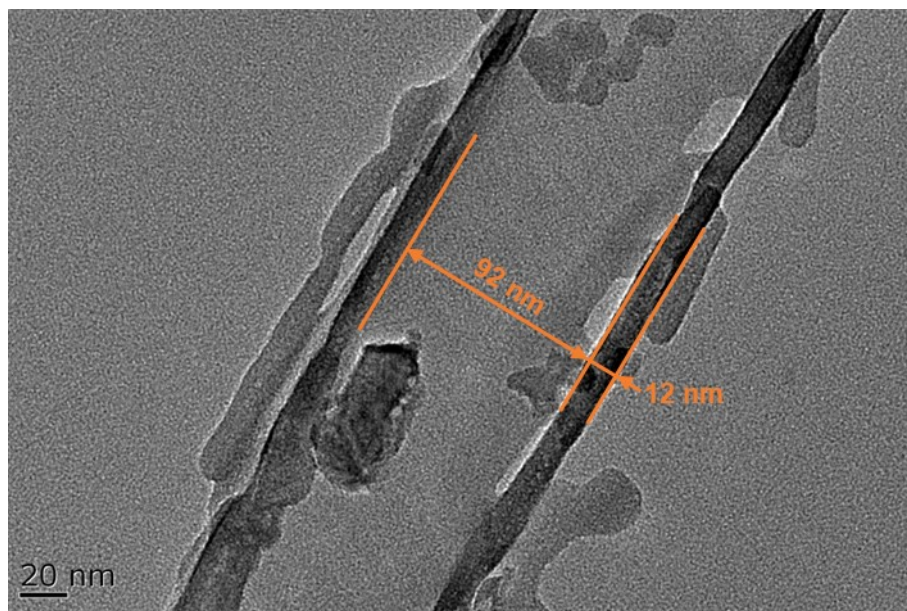


Fig. S4 SEM image of nanotubes anodized for 2 h without annealing

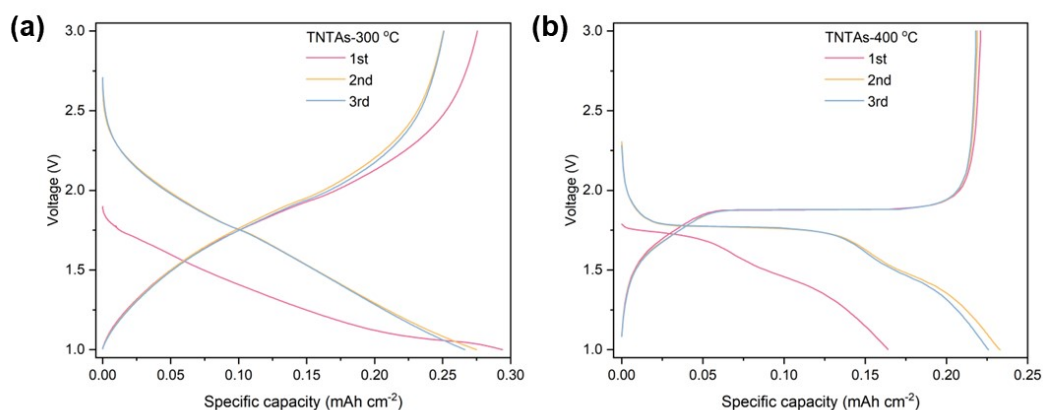


Fig. S5 Galvanostatic charge and discharge curves: (a) TNTAs annealed at 300 °C and (b) TNTAs annealed at 400 °C between 3.0 V and 1.0 V at 0.1 mA cm<sup>-2</sup>

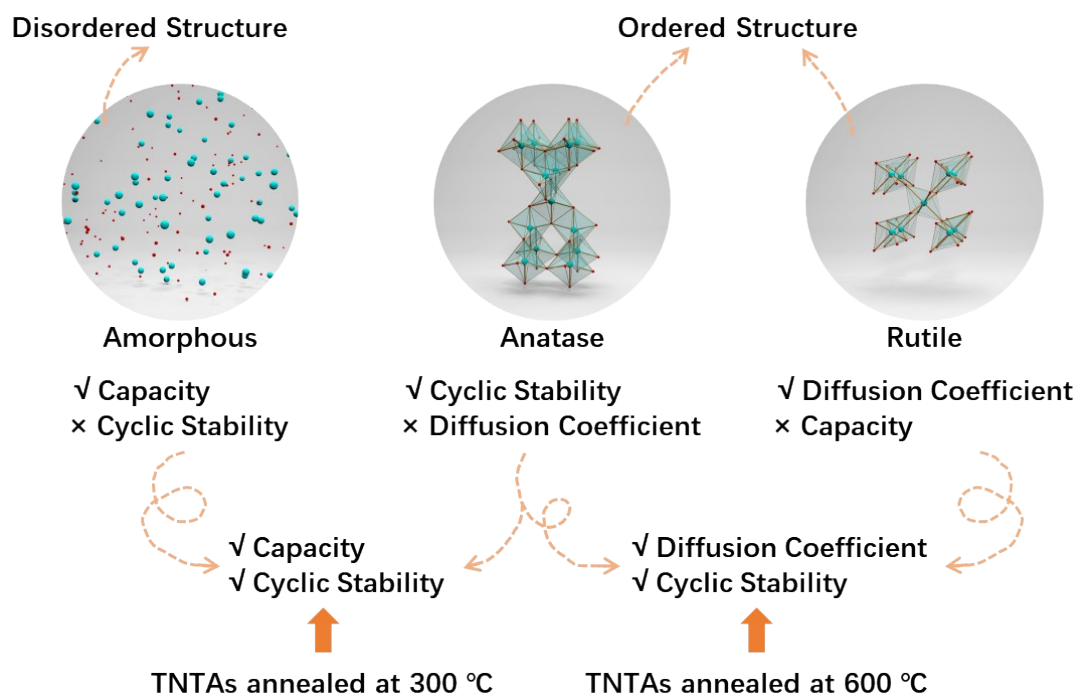


Fig. S6 The properties of TNTAs with different phases